

IGBT Chip in NPT-technology

FEATURES:

- 1200V NPT technology
- 180µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

This chip is used for:

- SGP07N120
- Applications:
- drives, SMPS, resonant applications



Chip Type	V _{CE}	I Cn	Die Size	Package	Ordering Code	
SIGC16T120CS	1200V	8A	4.04 x 4 mm ²	sawn on foil	Q67050-A4113	

MECHANICAL PARAMETER:

Raster size	4.04 x 4 m			
Area total / active	16.16 / 10.4			
Emitter pad size	1.88x2.18			
Gate pad size	0.71x1.08			
Thickness	180	μm		
Wafer size	150	mm		
Flat position	0	deg		
Max.possible chips per wafer	898 pcs			
Passivation frontside	Photoimide			
Emitter metalization	3200 nm Al Si 1%			
Collector metalization 1400 nm Ni Ag –system suitable for epoxy and soft solder die bon		ding		
Die bond	electrically conductive glue or solder			
Wire bond	AI, ≤500µm			
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm			
Recommended Storage Environment	nt store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t_p limited by T_{jmax}	I _{cpuls}	24	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), $T_i=25$ °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
Taranicici			min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I _C =500 μ A	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =8A	2.5	3.1	3.6	V
Gate-emitter threshold voltage	V _{GE(th)}	I_C =350µA , V_{GE} = V_{CE}	3.0	4.0	5.0	
Zero gate voltage collector current	I _{CES}	$V_{CE} = 1200V$, $V_{GE} = 0V$			1	μA
Gate-emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			120	nA

DYNAMIC CHARACTERISTICS (tested at component):

Paramotor	Symbol	Conditions	Value			Unit
Falameter	Symbol		min.	typ.	max.	
Input capacitance	Ciss	V _{CE} =25V,	-	720	870	pF
Output capacitance	Coss	$V_{GE}=0V$,	-	90	110	
Reverse transfer capacitance	Crss	f=1MHz	-	50	60	

SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Paramotor	Symbol	I Conditions*	Value			Unit
	Symbol		min.	typ.	max.	
Turn-on delay time	t _{d(on)}	$T_j=25 \circ C$	-	27	35	ns
Rise time	t _r	<i>I</i> _C =8A	-	29	38	
Turn-off delay time	$t_{d(off)}$	$V_{GE} = +15/0V$, $R_{C} = 47Q$	-	440	570	
Fall time	t _f	····	-	21	27	

* switching conditions different to LowLoss, Standard, IGBT3; under comparable switching conditions 40% faster than Standard. Values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:



Die-Size 4040 um x 4000 um



FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

SGP07N120

Package : TO220

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

Published by Infineon Technologies AG, Bereich Kommunikation St.-Martin-Strasse 53, D-81541 München © Infineon Technologies AG 2002 All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Representatives world-wide (see address list).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and / or maintain and sustain and / or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.